

CE2F3P

on-chip resistor NPN silicon epitaxial transistor For mid-speed switching

The CE2F3P is a transistor of on-chip high hFE resistor incorporating dumper diode in collector to emitter as protect elements. This transistor is ideal for actuator drives of OA equipments and electric equipments.

FEATURES

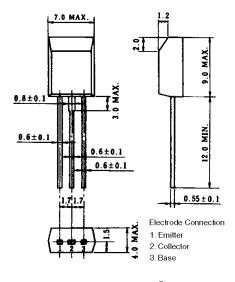
- On-chip bias resistor: $R_1 = 2.2 \text{ k}\Omega$, $R_2 = 10 \text{ k}\Omega$
- Low power consumption during driving: Vol = 0.12 V @Vl = 5.0 V, Ic = 0.5 A
- On-chip dumper diode for reverse cable

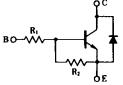
ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

| Parameter | Symbol | Ratings | Unit |
|------------------------------|--------------------|-------------|------|
| Collector to base voltage | Vсво | 60 | V |
| Collector to emitter voltage | VCEO | 60 | V |
| Emitter to base voltage | VEBO | 15 | V |
| Collector current (DC) | Ic(DC) | ±2.0 | Α |
| Collector current (Pulse) | Ic(pulse) * | ±3.0 | Α |
| Base current (DC) | I _{B(DC)} | 0.03 | Α |
| Total power dissipation | Рт | 1.0 | W |
| Junction temperature | Tj | 150 | °C |
| Storage temperature | T _{stg} | -55 to +150 | °C |

^{*} PW ≤ 10 ms, duty cycle ≤ 50 %

PACKAGE DRAWING (UNIT: mm)





ELECTRICAL CHARACTERISTICS (Ta = 25°C)

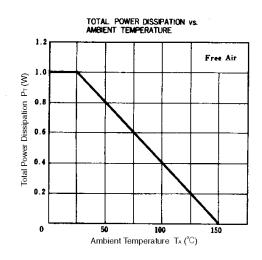
| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|--------------------------|---------------------|---|------|------|------|------|
| Collector cutoff current | Ісво | V _{CB} = 40 V, I _E = 0 | | | 100 | nA |
| DC current gain | h _{FE1} ** | Vce = 5.0 V, Ic = 0.2 A | 700 | 1200 | | _ |
| DC current gain | h _{FE2} ** | Vce = 5.0 V, Ic = 1.0 A | 1000 | 1600 | 3000 | _ |
| DC current gain | hFE3 ** | Vce = 5.0 V, Ic = 2.0 A | 500 | 1200 | | _ |
| Low level output voltage | Vol ** | V _I = 5.0 V, Ic = 0.5 A | | 0.12 | 0.3 | V |
| Low level input voltage | VIL ** | Vcε = 12 V, Ic = 100 μA | | 0.5 | 0.4 | V |
| Input resistance 1 | R ₁ | | 1.54 | 2.2 | 2.86 | kΩ |
| Input resistance 2 | R ₂ | | 7.0 | 10.0 | 13.0 | kΩ |
| Turn-on time | ton | Ic = 1.0 A | | 0.4 | | μs |
| Storage time | tstg | Іві = –Ів2 = 10 mA | | 1.4 | | μs |
| Fall time | tf | $V_{CC} = 20 \text{ V}, \text{ RL} = 20 \Omega$ | | 0.5 | | μs |

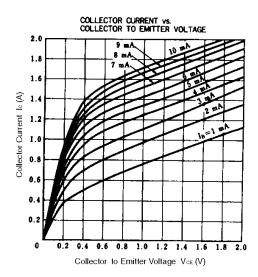
^{**} Pulse test PW \leq 350 μ s, duty cycle \leq 2 %

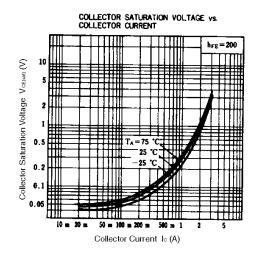
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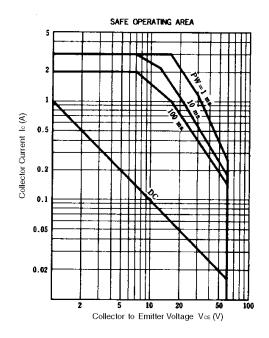


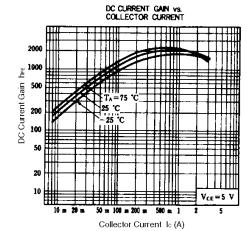
TYPICAL CHARACTERISTICS (Ta = 25°C)

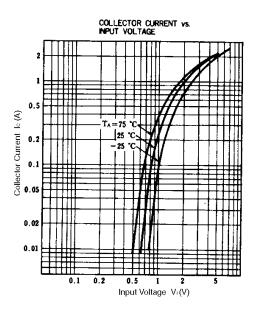


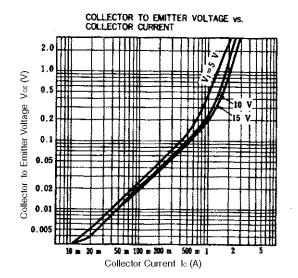


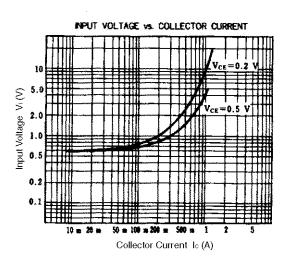












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